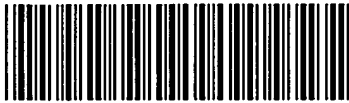


**Search Notes**

Application/Control No.

10/749,917

Examiner

Benny Lee

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
333	238, 246	8/31/2005	BTL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR